

MOS FIELD EFFECT TRANSISTOR μ PA2701GR

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

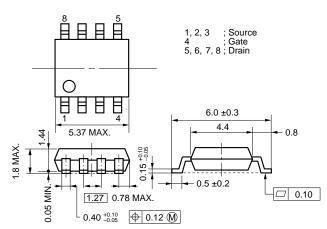
The μ PA2701GR is N-Channel MOS Field Effect Transistor designed for DC/DC converters and power management applications of notebook computers.

FEATURES

- Low on-state resistance $R_{DS(on)1} = 7.5 \text{ m}\Omega \text{ MAX}. (V_{GS} = 10 \text{ V}, I_D = 7.0 \text{ A})$ $R_{DS(on)2} = 11.6 \text{ m}\Omega \text{ MAX}. (V_{GS} = 4.5 \text{ V}, I_D = 7.0 \text{ A})$
- Low Ciss: Ciss = 1200 pF TYP. (VDs = 10 V, VGs = 0 V)
- Small and surface mount package (Power SOP8)

ORDERING INFORMATION

PART NUMBER	PACKAGE				
μPA2701GR	Power SOP8				

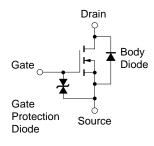


PACKAGE DRAWING (Unit: mm)

ABSOLUTE MAXIMUM RATINGS (TA = 25°C, All terminals are connected.)

Drain to Source Voltage (Vgs = 0 V)	VDSS	30	V	
Gate to Source Voltage (VDS = 0 V)	Vgss	±20	V	
Drain Current (DC)	ID(DC)	±14	А	
Drain Current (pulse) ^{Note1}	D(pulse)	±56	А	
Total Power Dissipation $(T_A = 25^{\circ}C)^{Note2}$	Рт	2.0	W	
Channel Temperature	Tch	150	°C	
Storage Temperature	Tstg	-55 to +150	°C	
Single Avalanche Current Note3	las	14	А	
Single Avalanche Energy Note3	Eas	19.6	mJ	

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

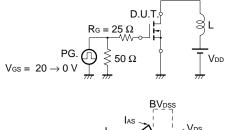
- 2. Mounted on ceramic substrate of 1200 mm² x 2.2 mm
- 3. Starting T_{ch} = 25°C, V_{DD} = 15 V, R_G = 25 Ω , L = 100 μ H, V_{GS} = 20 \rightarrow 0 V
- **Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

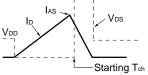
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ELECTRICAL CHARACTERISTICS (TA = 25°C, All ter	minals are connected.)
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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 30 V, V _{GS} = 0 V			10	μA
Gate Leakage Current	lgss	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 7.0 A	7	14		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, Id = 7.0 A		6.2	7.5	mΩ
	RDS(on)2	Vgs = 4.5 V, Id = 7.0 A		8.7	11.6	mΩ
	RDS(on)3	Vgs = 4.0 V, Id = 7.0 A		10.3	13.7	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		1200		pF
Output Capacitance	Coss	V _{GS} = 0 V		500		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		160		pF
Turn-on Delay Time	td(on)	V _{DD} = 15 V, I _D = 7.0 A		10		ns
Rise Time	tr	V _{GS} = 10 V		13		ns
Turn-off Delay Time	td(off)	R _G = 10 Ω		44		ns
Fall Time	tr			11		ns
Total Gate Charge	QG	V _{DD} = 15 V		12		nC
Gate to Source Charge	QGS	V _{GS} = 5 V		4		nC
Gate to Drain Charge	Qgd	I _D = 14 A		6		nC
Body Diode Forward Voltage	VF(S-D)	IF = 14 A, V _{GS} = 0 V		0.8	1.2	V
Reverse Recovery Time	trr	IF = 14 A, VGS = 0 V		32		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ μs		27		nC

TEST CIRCUIT 1 AVALANCHE CAPABILITY





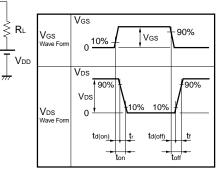
TEST CIRCUIT 2 SWITCHING TIME

D.U.T.

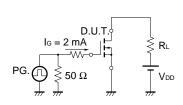
₩~~∽ Rg



 $\tau = 1 \,\mu s$ Duty Cycle $\leq 1\%$

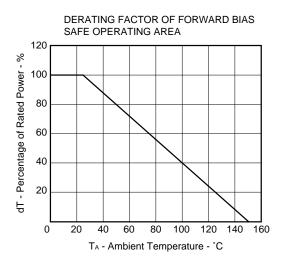


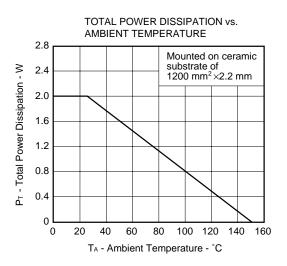
TEST CIRCUIT 3 GATE CHARGE



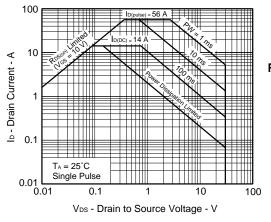
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TYPICAL CHARACTERISTICS (TA = 25°C)

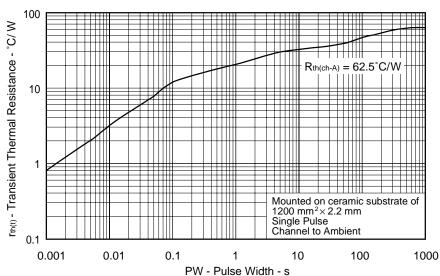




FORWARD BIAS SAFE OPERATING AREA



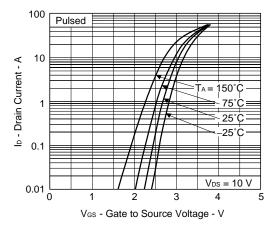
Remark Mounted on ceramicsubstrate of 1200 mm² x 2.2 mm

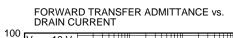


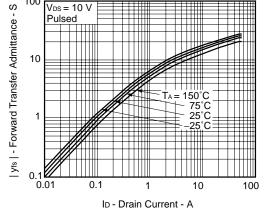
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

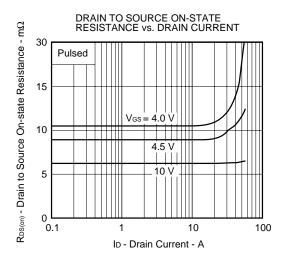
Data Sheet G15714EJ2V0DS

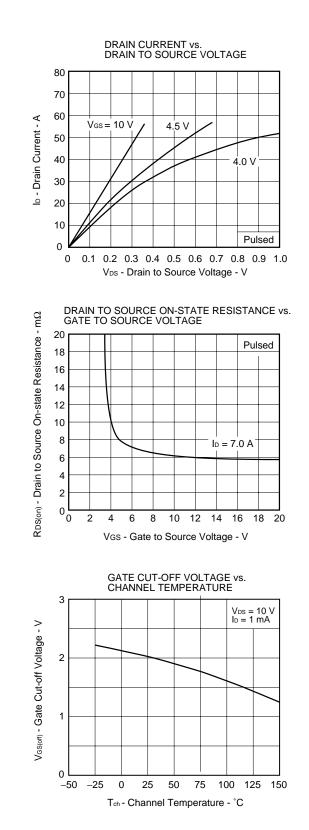
FORWARD TRANSFER CHARACTERISTICS

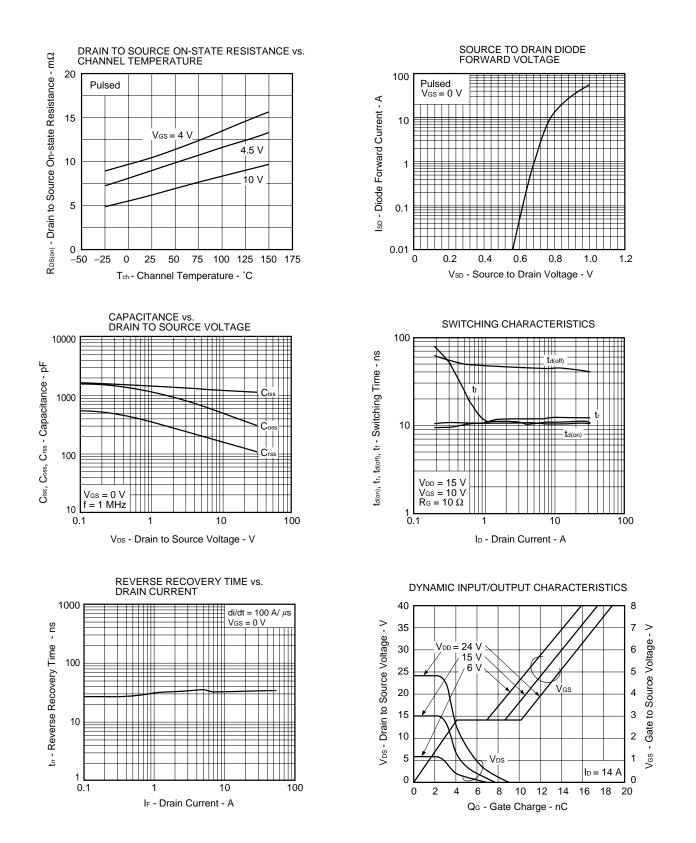












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